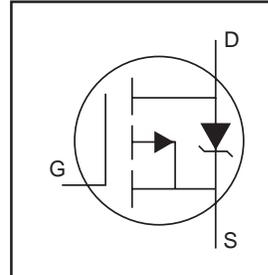


# IRFI9610GPbF

HEXFET® Power MOSFET

- Isolated Package
- High Voltage Isolation=2.5KVRMS ⑤
- Sink to Lead Creepage Dist.=4.8mm
- P-Channel
- Dynamic dv/dt Rating
- Low thermal Resistance
- Lead-Free



$V_{DSS} = -200V$
$R_{DS(on)} = 3.0\Omega$
$I_D = -2.0A$

## Description

Third Generation HEXFETs from International Rectifier provide the designer with the best combination of fast switching, ruggedized device design, low on-resistance and cost-effectiveness. Third Generation HEXFETs from International Rectifier provide the designer with the best combination of fast switching, ruggedized device design, low on-resistance and cost-effectiveness.

The TO-220 Fullpak eliminates the need for additional insulating hardware in commercial-industrial applications. The moulding compound used provides a high isolation capability and a low thermal resistance between the tab and external heatsink. This isolation is equivalent to using a 100 micron mica barrier with standard TO-220 product. The Fullpak is mounted to a heatsink using a single clip or by a single screw fixing.



## Absolute Maximum Ratings

	Parameter	Max.	Units
$I_D @ T_C = 25^\circ C$	Continuous Drain Current, $V_{GS} @ -10V$	-2.0	A
$I_D @ T_C = 100^\circ C$	Continuous Drain Current, $V_{GS} @ -10V$	-1.3	
$I_{DM}$	Pulsed Drain Current ①	-8.0	
$P_D @ T_C = 25^\circ C$	Power Dissipation	27	W
	Linear Derating Factor	0.22	W/°C
$V_{GS}$	Gate-to-Source Voltage	$\pm 20$	V
$E_{AS}$	Single Pulse Avalanche Energy②	100	mJ
$I_{AR}$	Avalanche Current③	-2.0	A
$E_{AR}$	Repetitive Avalanche Energy④	2.7	mJ
dv/dt	Peak Diode Recovery dv/dt ⑤	-11	V/ns
$T_J$	Operating Junction and	-55 to + 150	°C
$T_{STG}$	Storage Temperature Range		
	Soldering Temperature, for 10 seconds		
	Mounting torque, 6-32 or M3 screw	10 lbf•in (1.1N•m)	

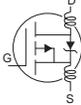
## Thermal Resistance

	Parameter	Typ.	Max.	Units
$R_{\theta JC}$	Junction-to-Case	---	4.6	°C/W
$R_{\theta JA}$	Junction-to-Ambient	---	65	

# IRFI9610GPbF

International  
**IOR** Rectifier

## Electrical Characteristics @ $T_J = 25^\circ\text{C}$ (unless otherwise specified)

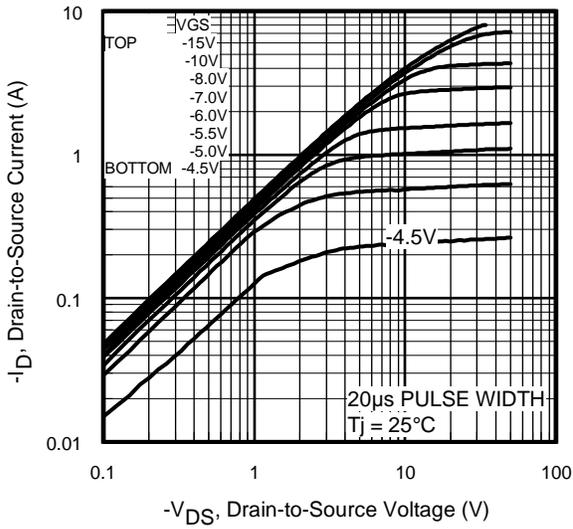
	Parameter	Min.	Typ.	Max.	Units	Conditions
$V_{(BR)DSS}$	Drain-to-Source Breakdown Voltage	-200	—	—	V	$V_{GS} = 0V, I_D = -250\mu A$
$\Delta V_{(BR)DSS}/\Delta T_J$	Breakdown Voltage Temp. Coefficient	—	-0.22	—	V/°C	Reference to $25^\circ\text{C}$ , $I_D = -1\text{mA}$
$R_{DS(on)}$	Static Drain-to-Source On-Resistance	—	—	3.0	$\Omega$	$V_{GS} = -10V, I_D = -1.2A$ ④
$V_{GS(th)}$	Gate Threshold Voltage	-2.0	—	-4.0	V	$V_{DS} = V_{GS}, I_D = -250\mu A$
$g_{fs}$	Forward Transconductance	0.7	—	—	S	$V_{DS} = -50V, I_D = -1.2A$
$I_{DSS}$	Drain-to-Source Leakage Current	—	—	-100	$\mu A$	$V_{DS} = -200V, V_{GS} = 0V$
		—	—	-500		$V_{DS} = -160V, V_{GS} = 0V, T_J = 125^\circ\text{C}$
$I_{GSS}$	Gate-to-Source Forward Leakage	—	—	100	nA	$V_{GS} = 20V$
	Gate-to-Source Reverse Leakage	—	—	-100		$V_{GS} = -20V$
$Q_g$	Total Gate Charge	—	—	13	nC	$I_D = -2.0A$
$Q_{gs}$	Gate-to-Source Charge	—	—	3.2		$V_{DS} = -160V$
$Q_{gd}$	Gate-to-Drain ("Miller") Charge	—	—	7.3		$V_{GS} = -10V$ , See Fig. 6 and 13 ④
$t_{d(on)}$	Turn-On Delay Time	—	12	—	ns	$V_{DD} = -100V$
$t_r$	Rise Time	—	17	—		$I_D = -2.0A$
$t_{d(off)}$	Turn-Off Delay Time	—	19	—		$R_G = 24\Omega$
$t_f$	Fall Time	—	15	—		$V_{GS} = -10V$ , See Fig. 10 ④
$L_D$	Internal Drain Inductance	—	4.5	—	nH	Between lead, 6mm (0.25in.) from package and center of die contact
$L_S$	Internal Source Inductance	—	7.5	—		
$C_{iss}$	Input Capacitance	—	180	—	pF	$V_{GS} = 0V$
$C_{oss}$	Output Capacitance	—	66	—		$V_{DS} = -25V$
$C_{rss}$	Reverse Transfer Capacitance	—	12	—		$f = 1.0\text{MHz}$ , See Fig. 5

## Source-Drain Ratings and Characteristics

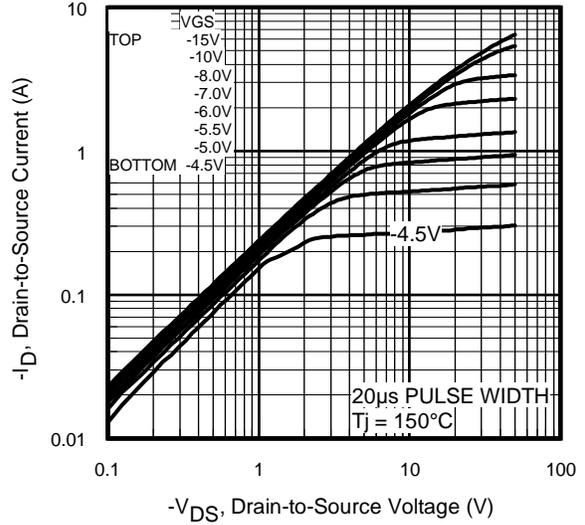
	Parameter	Min.	Typ.	Max.	Units	Conditions
$I_S$	Continuous Source Current (Body Diode)	—	—	-2.0	A	MOSFET symbol showing the integral reverse p-n junction diode.
$I_{SM}$	Pulsed Source Current (Body Diode) ①	—	—	-8.0		
$V_{SD}$	Diode Forward Voltage	—	—	-5.8	V	$T_J = 25^\circ\text{C}, I_S = -2.0A, V_{GS} = 0V$ ②
$t_{rr}$	Reverse Recovery Time	—	130	200	ns	$T_J = 25^\circ\text{C}, I_F = -2.0A$
$Q_{rr}$	Reverse Recovery Charge	—	700	1050	nC	$di/dt = -100A/\mu s$ ③
$t_{on}$	Forward Turn-On Time	Intrinsic turn-on time is negligible (turn-on is dominated by $L_S + L_D$ )				

### Notes:

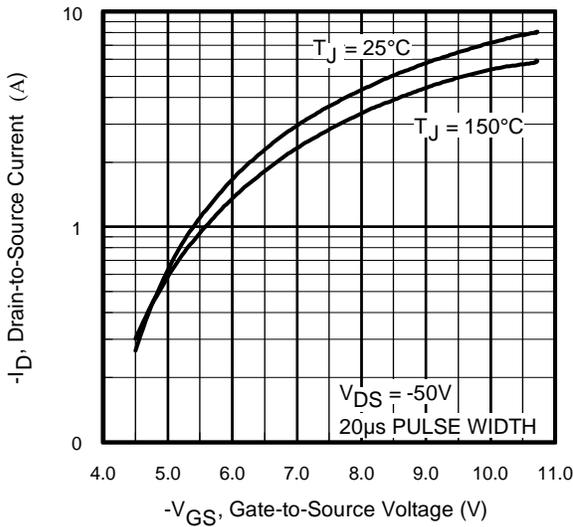
- ① Repetitive rating; pulse width limited by max. junction temperature. ( See fig. 11 )
- ② Starting  $T_J = 25^\circ\text{C}$ ,  $L = 51\text{mH}$   
 $R_G = 25\Omega, I_{AS} = -2.0A$ . (See Figure 12)
- ③  $I_{SD} \leq -2.0A, di/dt \leq -250A/\mu s, V_{DD} \leq V_{(BR)DSS}, T_J \leq 150^\circ\text{C}$
- ④ Pulse width  $\leq 300\mu s$ ; duty cycle  $\leq 2\%$ .
- ⑤  $t = 60s, f = 60\text{Hz}$ .



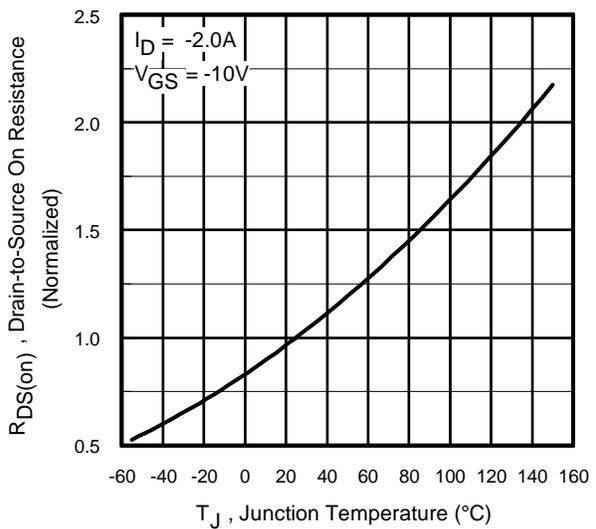
**Fig 1.** Typical Output Characteristics,  
 $T_J = 25^\circ\text{C}$



**Fig 2.** Typical Output Characteristics,  
 $T_J = 150^\circ\text{C}$

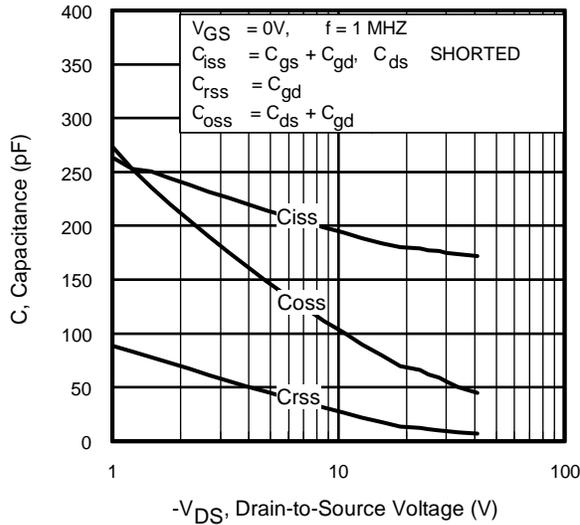


**Fig 3.** Typical Transfer Characteristics

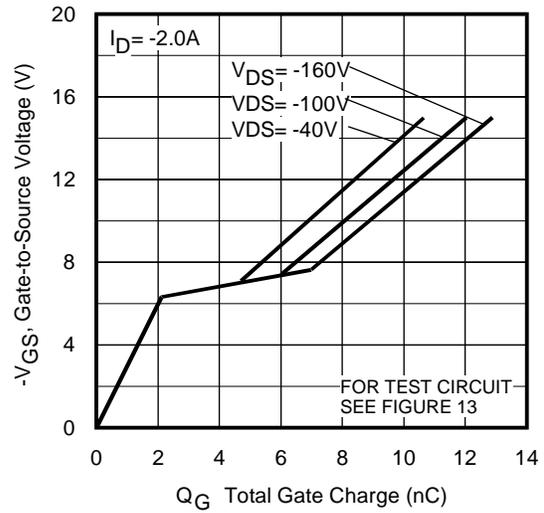


**Fig 4.** Normalized On-Resistance  
Vs. Temperature

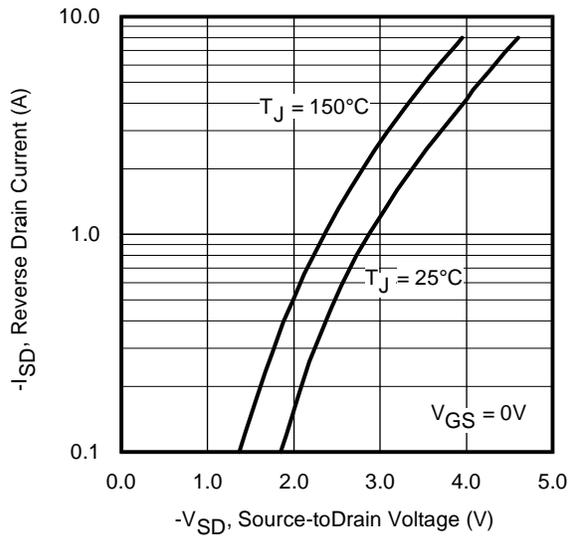
# IRFI9610GPbF



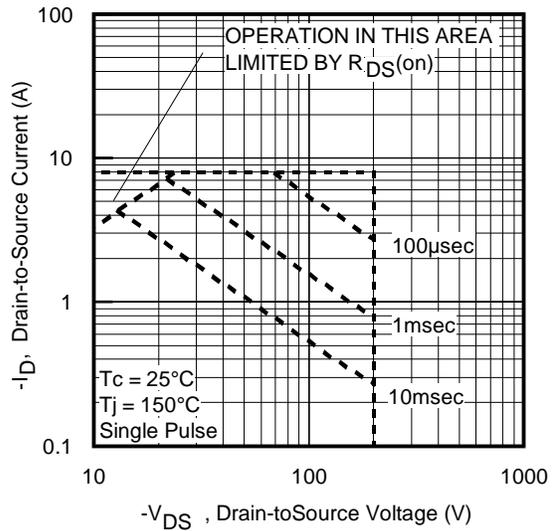
**Fig 5.** Typical Capacitance Vs. Drain-to-Source Voltage



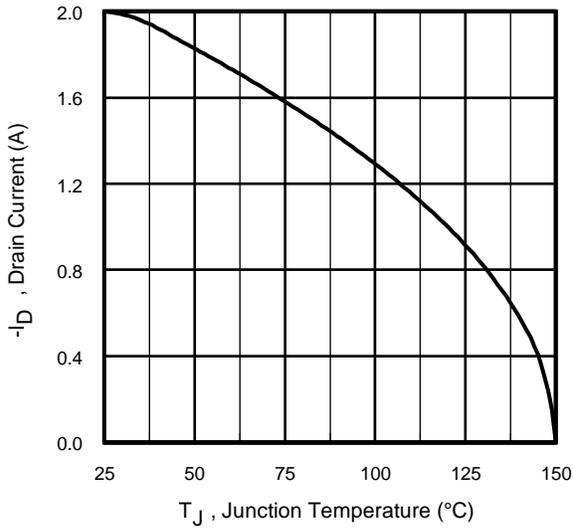
**Fig 6.** Typical Gate Charge Vs. Gate-to-Source Voltage



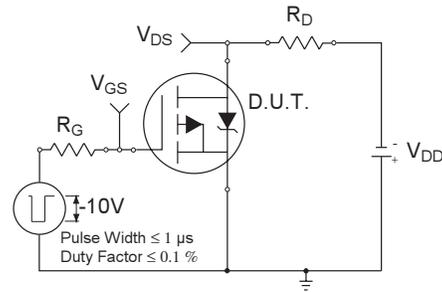
**Fig 7.** Typical Source-Drain Diode Forward Voltage



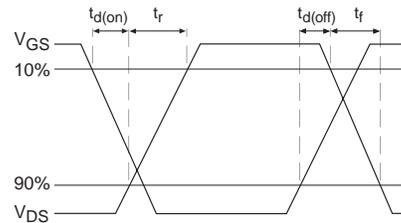
**Fig 8.** Maximum Safe Operating Area



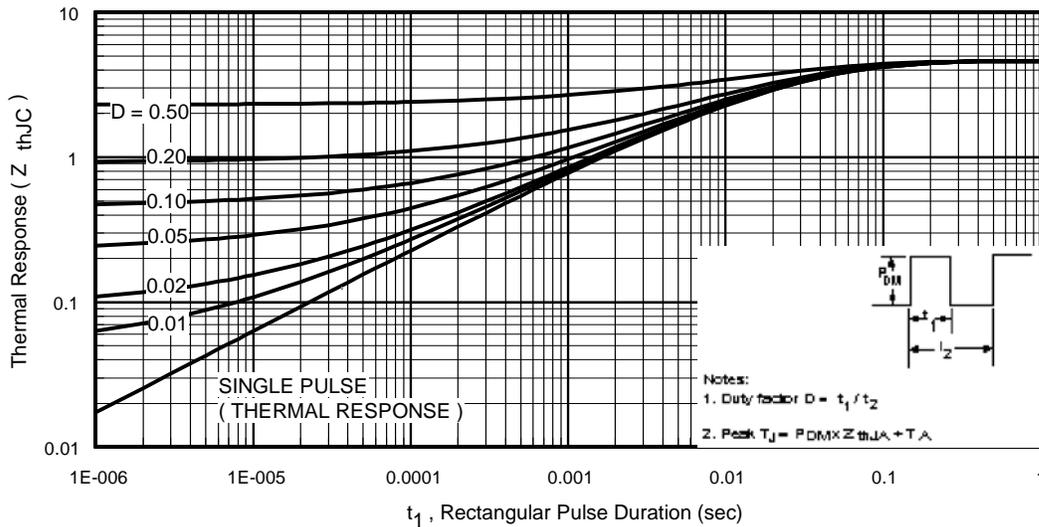
**Fig 9.** Maximum Drain Current Vs. Case Temperature



**Fig 10a.** Switching Time Test Circuit

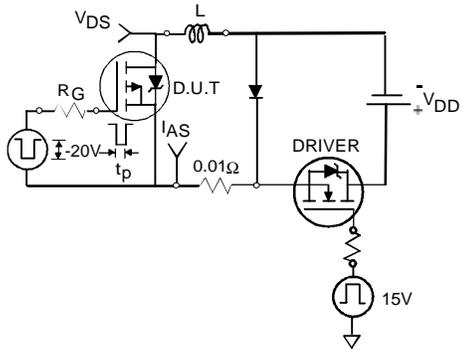


**Fig 10b.** Switching Time Waveforms

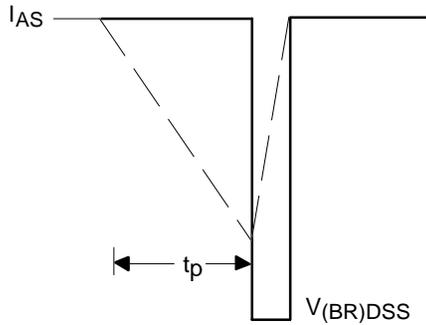


**Fig 11.** Maximum Effective Transient Thermal Impedance, Junction-to-Case

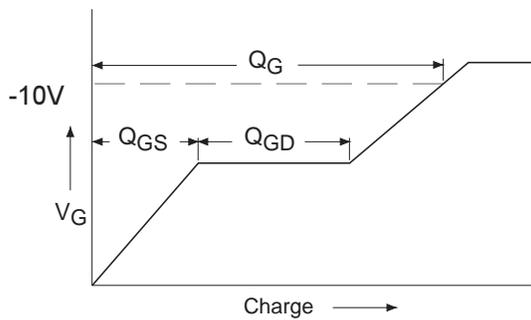
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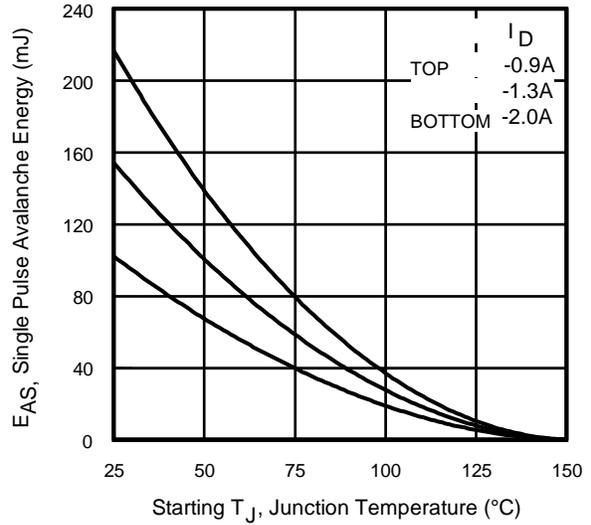
**Fig 12a.** Unclamped Inductive Test Circuit



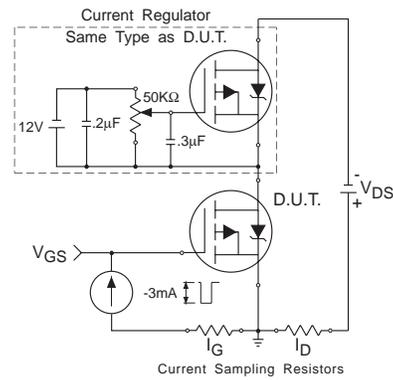
**Fig 12b.** Unclamped Inductive Waveforms



**Fig 13a.** Basic Gate Charge Waveform

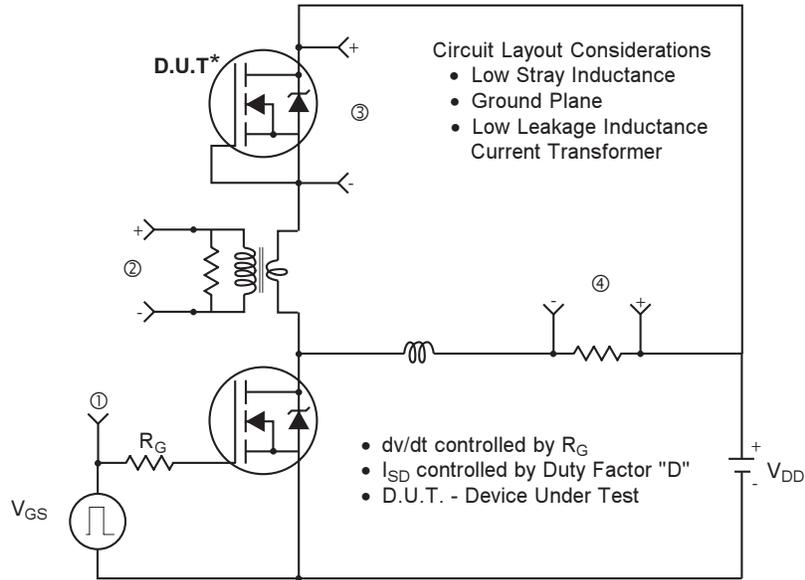


**Fig 12c.** Maximum Avalanche Energy Vs. Drain Current

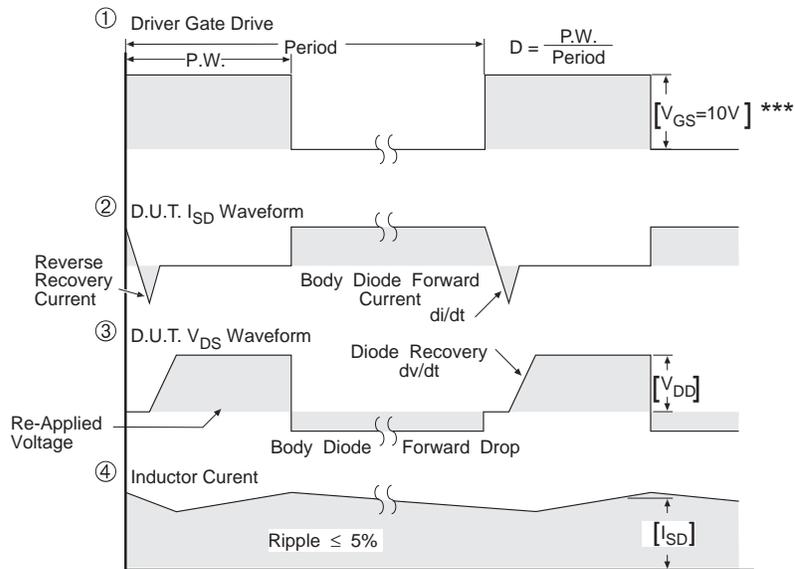


**Fig 13b.** Gate Charge Test Circuit

## Peak Diode Recovery dv/dt Test Circuit



\* Reverse Polarity of D.U.T for P-Channel



\*\*\*  $V_{GS} = 5.0V$  for Logic Level and 3V Drive Devices

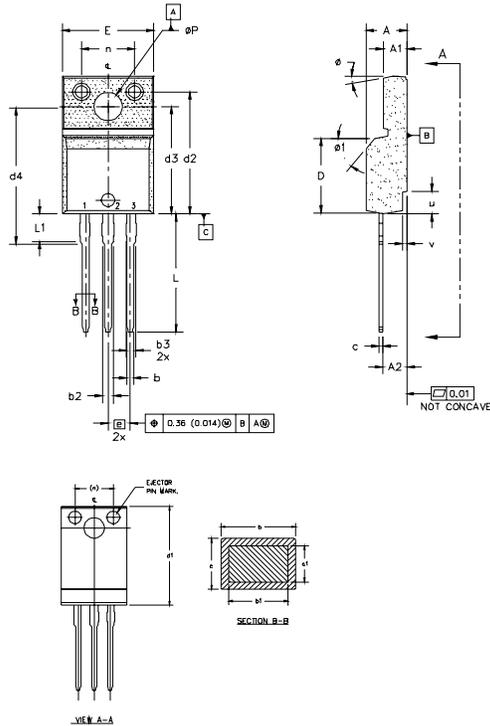
**Fig 14.** For P-Channel HEXFETS

# IRFI9610GPbF

## TO-220 Full-Pak Package Outline



Dimensions are shown in millimeters (inches)



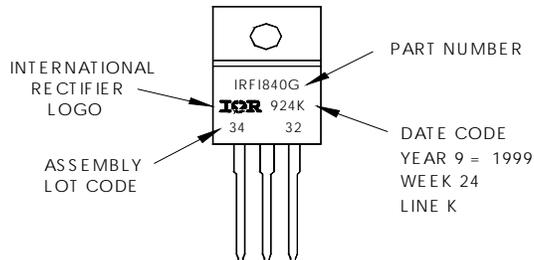
- NOTES:
- 1.0 DIMENSIONING AND TOLERANCING PER ASME Y14.5 M-1994.
  - 2.0 DIMENSIONS ARE SHOWN IN MILLIMETERS (INCHES).
  - 3.0 LEAD DIMENSION AND FINISH UNCONTROLLED IN L1.
  - 4.0 DIMENSION D & E DO NOT INCLUDE MOLD FLASH. MOLD FLASH SHALL NOT EXCEED 0.005" (0.127) PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTERMOST EXTREMES OF THE PLASTIC BODY.
  - 5.0 DIMENSION b1 APPLY TO BASE METAL ONLY.
  - 6.0 STEP OPTIONAL ON PLASTIC BODY DEFINED BY DIMENSIONS u & v.
  - 7.0 CONTROLLING DIMENSION : INCHES.

SYMBOL	DIMENSIONS				NOTES	LEAD ASSIGNMENTS
	MILLIMETERS		INCHES			
A	4.57	4.83	0.180	0.190		HEXFET 1.- GATE 2.- DRAIN 3.- SOURCE
A1	2.57	2.83	0.101	0.114		
A2	2.51	2.85	0.099	0.112		
b	0.622	0.89	0.024	0.035	5	
b1	0.622	0.838	0.024	0.033		
b2	1.229	1.400	0.048	0.056		
b3	1.229	1.400	0.048	0.056	4	
c	0.440	0.629	0.017	0.025		
c1	0.440	0.584	0.017	0.023		
D	8.65	9.80	0.341	0.386	4	IGBTs, CoPACK 1.- GATE 2.- COLLECTOR 3.- EMITTER
d1	15.80	16.12	0.622	0.636		
d2	13.97	14.22	0.550	0.560		
d3	12.30	12.92	0.484	0.509	4	
d4	8.64	9.91	0.340	0.390		
E	10.36	10.63	0.408	0.419		
e	2.54 BSC		0.100 BSC		3	
L	13.20	13.73	0.520	0.541		
L1	3.10	3.50	0.122	0.138		
n	6.05	6.15	0.238	0.242	6	
øP	3.05	3.45	0.120	0.136		
u	2.40	2.50	0.094	0.098		
v	0.40	0.50	0.016	0.020	6	
w	3"	7"	3"	7"		
ø1	45°		45°			

## TO-220 Full-Pak Part Marking Information

EXAMPLE: THIS IS AN IRFI840G  
WITH ASSEMBLY  
LOT CODE 3432  
ASSEMBLED ON WW 24 1999  
IN THE ASSEMBLY LINE "K"

**Note:** "P" in assembly line position indicates "Lead-Free"



Data and specifications subject to change without notice.  
Qualification Standards can be found on IR's Web site.



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